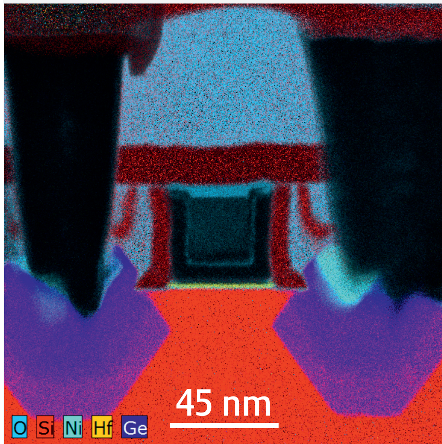
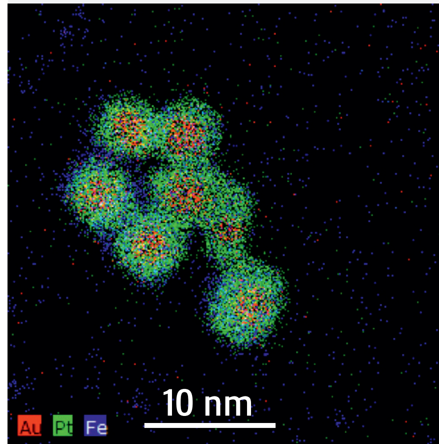
ChemiSTEM™ technology
A revolution in EDX analytics

Large map, all elements



45 nm PMOS structure
600 x 600 pixels
Drift correction applied

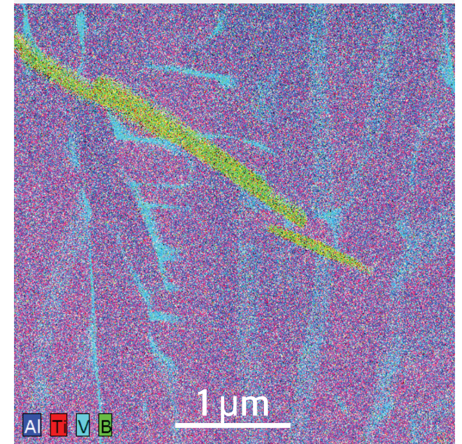
High sensitivity



Au/Pt(Fe) core/shell particles < 5 nm
300 x 300 pixels recorded in < 4 min

Sample courtesy of C. Wang, V. Stamenkovic, N. Markovic and N.J. Zaluzec, Argonne National Laboratory

Light element detection



Boron distribution in TiB/TiAl
512 x 512 pixels recorded in < 5 min
100 µsec dwell time; multiple frames

Sample courtesy of Ohio State University

Tecnai Osiris™

ChemiSTEM™ technology, higher beam current and revolutionary X-ray detection capability:

- Largest solid angle for EDX detection: 0.9 sr
- Ultimate speed: elemental maps in minutes
- Highest sensitivity for light elements and low concentrations

Learn more at FEI.com/research

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